

IN THE ABSTRACT:

The Abstract as amended below with a replacement Abstract shows added text with underlining and deleted text with ~~striketrough~~.

Please DELETE the Abstract in its entirety and substitute the attached new Abstract.

An apparatus enables a high quality test to be carried out within a short time, without forcing a severe design limitation on the designer and without an expensive tester. The apparatus includes a pattern generator built in an integrated circuit to generate pseudo random patterns as test patterns. A plurality of shift registers are configured with sequential circuit elements inside said integrated circuit. An automatic test pattern generating unit generates ATPG patterns. A pattern modifier modifies a portion, to which a predetermined value is required to be set in order to detect a fault, in said pseudo random patterns generated by said pattern generator, on a basis of said ATPG patterns, and inputs said modified pseudo random patterns to said shift registers.